

## Features

- $I_{T(RMS)} = 0.8 \text{ A}$
- $V_{DRM}, V_{RRM} = 600 \text{ V}$
- $I_{GT} = 30 \text{ to } 200 \mu\text{A}$

## Applications

- Limited gate current topologies
- Ground fault circuit interrupters
- Overvoltage crowbar protection in power supplies
- Protection in electronic ballasts
- Capacitive discharge ignitions
- Ignitors (lighting, oven...)

## Description

The MCR100-6 SCR can be used as on/off function in applications where topology does not offer high current for gate triggering.

This device is optimized in forward voltage drop and inrush current capabilities for reduced power losses and high reliability in harsh environments.

**Table 1. Device summary**

$I_{T(RMS)}$	0.8 A
$V_{DRM} / V_{RRM}$	600 V
$I_{GT}$	30 to 200 $\mu\text{A}$

# 1 Characteristics

**Table 1. Absolute ratings (limiting values,  $T_j = 25 \text{ }^\circ\text{C}$  unless otherwise specified)**

Symbol	Parameter			Value	Unit	
$I_{T(RMS)}$	On-state rms current (180 °Conduction angle)	TO-92	$T_L = 83 \text{ }^\circ\text{C}$	0.8	A	
		SOT-223	$T_c = 107 \text{ }^\circ\text{C}$			
$I_{T(AV)}$	Average on-state current (180 °Conduction angle)	TO-92	$T_L = 83 \text{ }^\circ\text{C}$	0.5	A	
		SOT-223	$T_c = 107 \text{ }^\circ\text{C}$			
$I_{TSM}$	Non repetitive surge peak on-state current	$t_p = 8.3 \text{ ms}$	$T_j = 25 \text{ }^\circ\text{C}$	10	A	
		$t_p = 10 \text{ ms}$		9		
$I^2t$	$I^2t$ Value for fusing	$t_p = 10 \text{ ms}$	$T_j = 25 \text{ }^\circ\text{C}$	0.4	$\text{A}^2\text{s}$	
$di/dt$	Critical rate of rise of on-state current $I_G = 2 \times I_{GT}, t_r \leq 100 \text{ ns}$	$F = 60 \text{ Hz}$	$T_j = 125 \text{ }^\circ\text{C}$	50	$\text{A}/\mu\text{s}$	
$I_{GM}$	Peak gate current	$t_p = 20 \mu\text{s}$	$T_j = 125 \text{ }^\circ\text{C}$	1	A	
$P_{G(AV)}$	Average gate power dissipation	$T_j = 125 \text{ }^\circ\text{C}$		0.1	W	
$T_{stg}$	Storage junction temperature range				- 40 to + 150	$^\circ\text{C}$
$T_j$	Operating junction temperature range				- 40 to + 125	

**Table 2. Electrical characteristics ( $T_j = 25\text{ }^\circ\text{C}$  unless otherwise specified)**

Symbol	Test conditions		Value	Unit	
$I_{GT}$	$V_D = 12\text{ V}, R_L = 140\ \Omega$	MIN.	30	$\mu\text{A}$	
		MAX.	200		
$V_{GT}$			0.8	V	
$V_{GD}$	$V_D = V_{DRM}, R_L = 3.3\text{ k}\Omega, R_{GK} = 1\text{ k}\Omega$	$T_j = 125\text{ }^\circ\text{C}$	MIN.	0.2	V
$V_{RG}$	$I_{RG} = 10\ \mu\text{A}$		MIN.	5	V
$I_H$	$I_T = 50\text{ mA}, R_{GK} = 1\text{ k}\Omega$		MAX.	5	mA
$I_L$	$I_G = 1\text{ mA}, R_{GK} = 1\text{ k}\Omega$		MAX.	6	mA
dV/dt	$V_D = 67\% V_{DRM}, R_{GK} = 1\text{ k}\Omega$	$T_j = 125\text{ }^\circ\text{C}$	MIN.	40	V/ $\mu\text{s}$

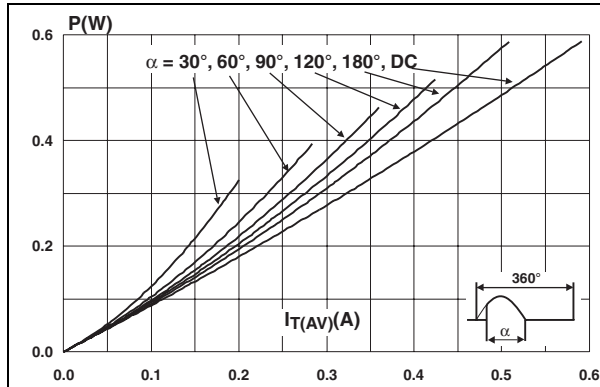
**Table 3. Static electrical characteristics**

Symbol	Test conditions		Value	Unit	
$V_{TM}$	$I_{TM} = 1\text{ A}, t_p = 380\ \mu\text{s}$	$T_j = 25\text{ }^\circ\text{C}$	MAX	1.35	V
$V_{TO}$	Threshold voltage	$T_j = 125\text{ }^\circ\text{C}$		0.85	V
$R_d$	Dynamic resistance			245	m $\Omega$
$I_{DRM} I_{RRM}$	$V_{DRM} = V_{RRM}, R_{GK} = 1\text{ k}\Omega$	$T_j = 25\text{ }^\circ\text{C}$		1	$\mu\text{A}$
		$T_j = 125\text{ }^\circ\text{C}$	100	$\mu\text{A}$	

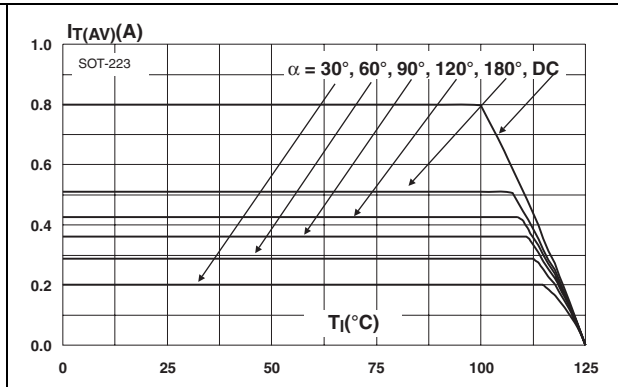
**Table4. Thermal resistances**

Symbol	Parameter		Value	Unit
$R_{th(j-l)}$	Junction to leads (DC)	TO-92	Max.	$^\circ\text{C/W}$
$R_{th(j-c)}$	Junction to case (DC)	SOT-223		
$R_{th(j-a)}$	Junction to ambient (DC)	TO-92		
		$S = 5\text{ cm}^2$ SOT-223		

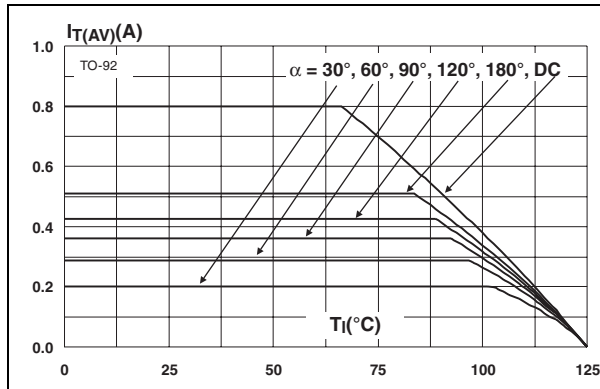
**Figure1. Maximum average power dissipation versus average on-state current**



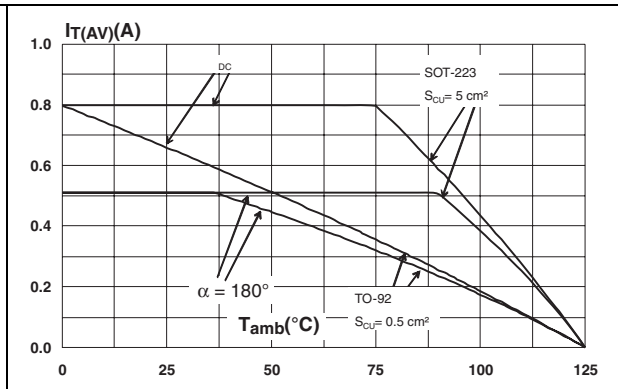
**Figure2. Average and DC on-state current versus case temperature (SOT-223)**



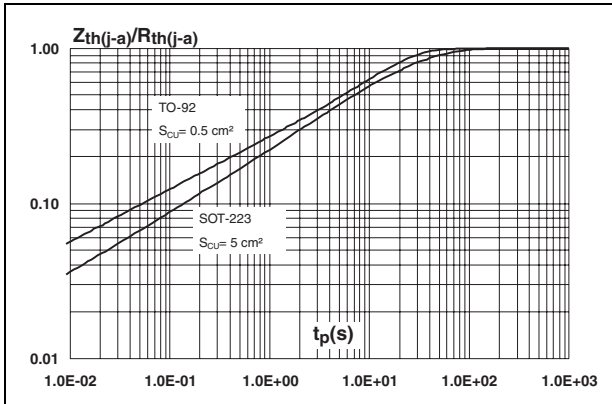
**Figure3. Average and DC on-state current versus lead temperature (TO-92)**



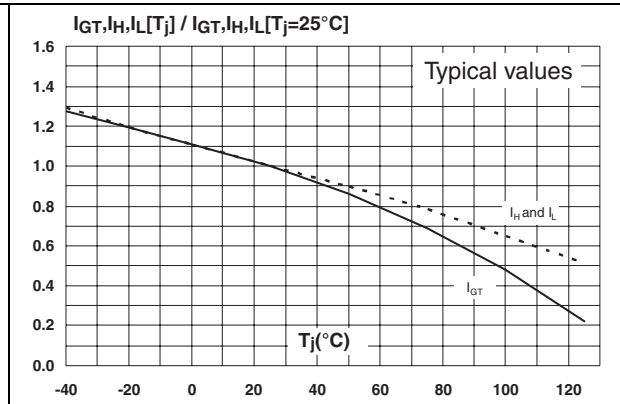
**Figure4. Average and DC on-state current versus ambient temperature (free air convection)**



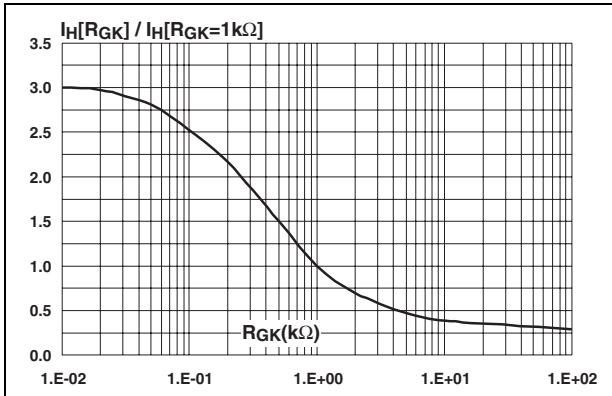
**Figure5. Relative variation of thermal impedance junction to ambient versus pulse duration**



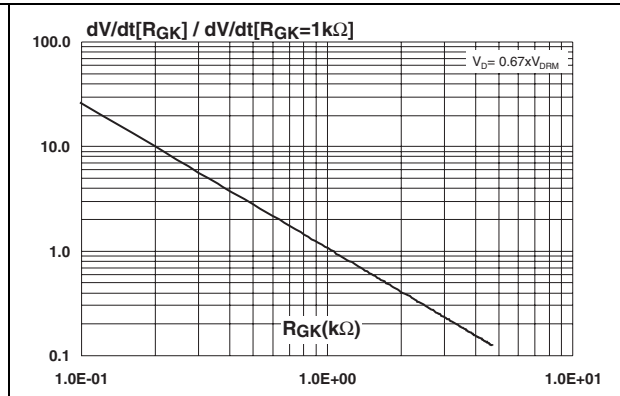
**Figure6. Relative variation of gate trigger, holding and latching current versus junction temperature**



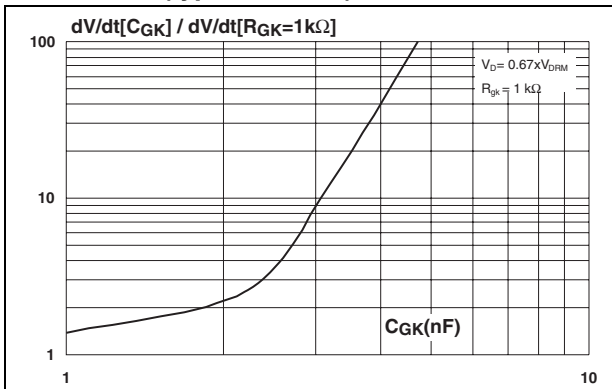
**Figure7. Relative variation of holding current versus gate-cathode resistance (typical values)**



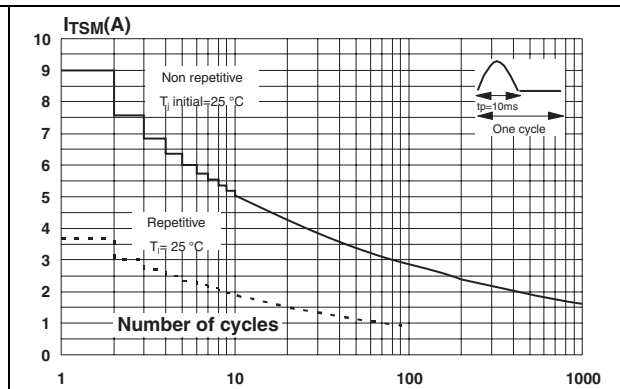
**Figure8. Relative variation of dV/dt immunity versus gate-cathode resistance (typical values)**



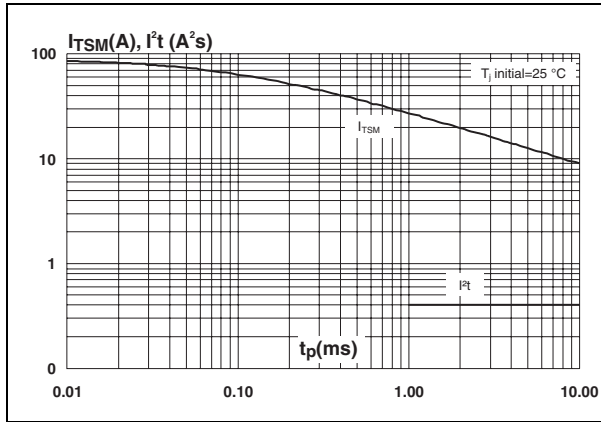
**Figure9. Relative variation of dV/dt immunity versus gate-cathode capacitance (typical values)**



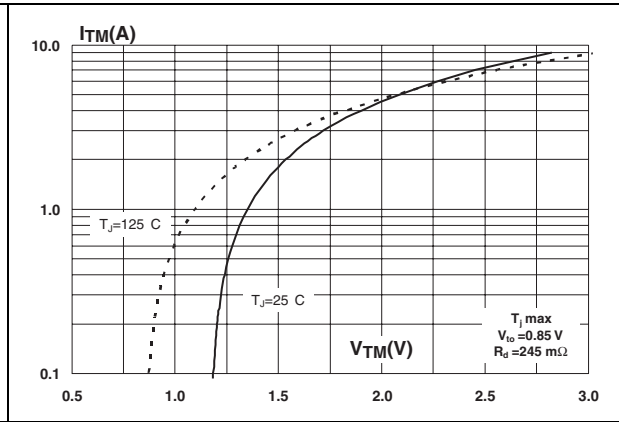
**Figure10. Surge peak on-state current versus number of cycles**



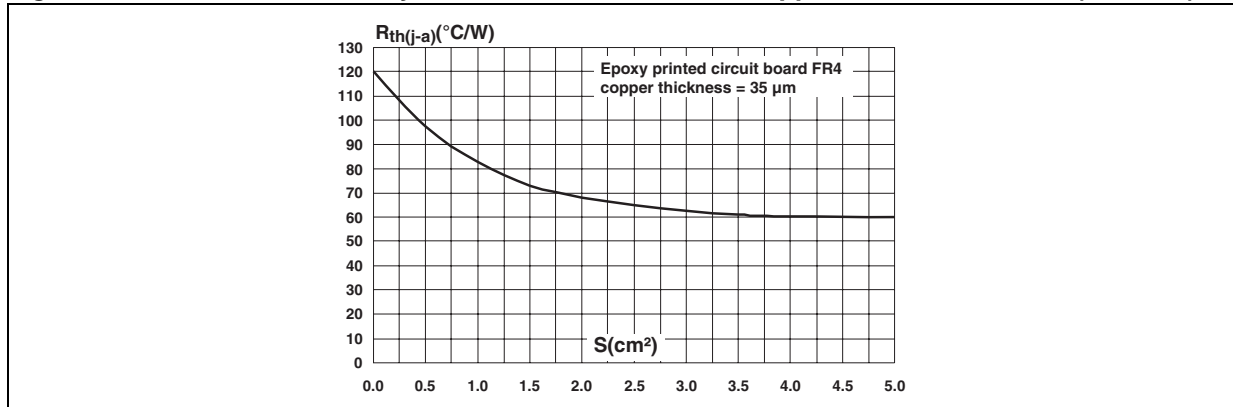
**Figure11. Non repetitive surge peak on state current for a sinusoidal pulse and corresponding value of  $I^2t$**



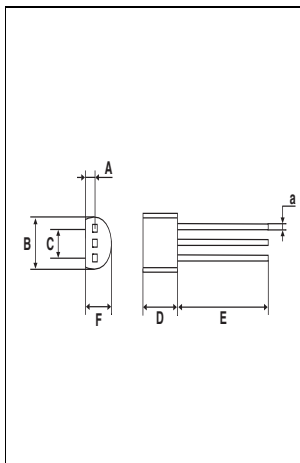
**Figure12. On-state characteristics (maximum values)**



**Figure13. Thermal resistance junction to ambient versus copper surface under tab (SOT-223)**

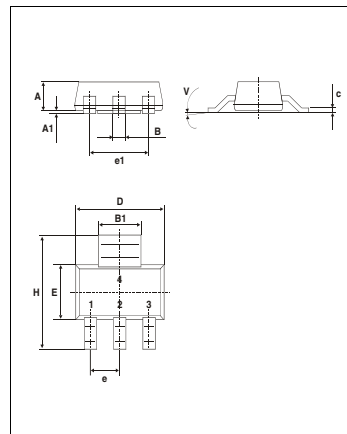


5. TO-92 (plastic) dimensions



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	-	1.35	-	-	0.053	-
B	-	-	4.70	-	-	0.185
C	-	2.54	-	-	0.100	-
D	4.40	-	-	0.173	-	-
E	12.70	-	-	0.500	-	-
F	-	-	3.70	-	-	0.146
a	-	-	0.50	-	-	0.019

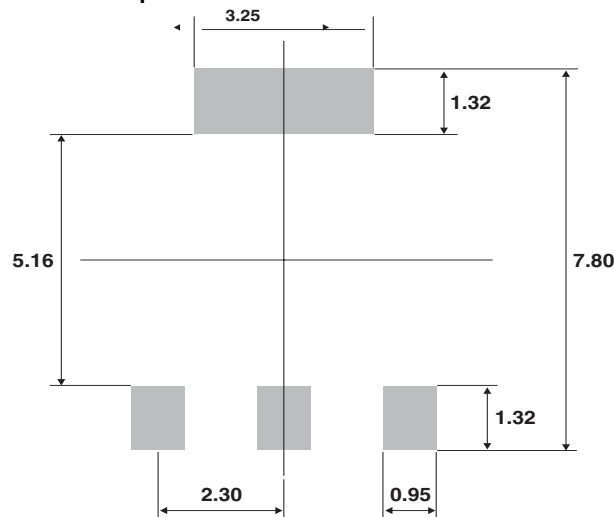
Table 6. SOT-223 dimensions



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A			1.80			0.071
A1		0.02	0.10		0.001	0.004
B	0.60	0.70	0.85	0.024	0.027	0.033
B1	2.90	3.00	3.15	0.114	0.118	0.124
c	0.24	0.26	0.35	0.009	0.010	0.014
D <sup>(1)</sup>	6.30	6.50	6.70	0.248	0.256	0.264
e		2.3			0.090	
e1		4.6			0.181	
E <sup>(1)</sup>	3.30	3.50	3.70	0.130	0.138	0.146
H	6.70	7.00	7.30	0.264	0.276	0.287
V	10° max					

1. Do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.15mm (0.006inches)

Figure 14. SOT-223 footprint



**IMPORTANT NOTICE – PLEASE READ CAREFULLY**

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